SN5473, SN54LS73A, SN7473, SN74LS73A
DUAL J-K FLIP-FLOPS WITH CLEAR

SDLS118

DECEMBER 1983 – REVISED MARCH 1988

- **Package Options Include Plastic "Small Outline" Packages, Flat Packages, and Plastic and Ceramic DIPs**
- **Dependable Texas Instruments Quality and Reliability**

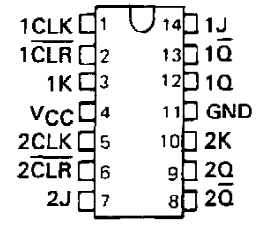
description

The '73, and 'H73, contain two independent J-K flip-flops with individual J-K, clock, and direct clear inputs. The '73, and 'H73, are positive pulse-triggered flip-flops. J-K input is loaded into the master while the clock is high and transferred to the slave on the high-to-low transition. For these devices the J and K inputs must be stable while the clock is high.

The 'LS73A contains two independent negative-edge-triggered flip-flops. The J and K inputs must be stable one setup time prior to the high-to-low clock transition for predictable operation. When the clear is low, it overrides the clock and data inputs forcing the Q output low and the $\overline{Q}$ output high.

The SN5473, SN54H73, and the SN54LS73A are characterized for operation over the full military temperature range of −55°C to 125°C. The SN7473, and the SN74LS73A are characterized for operation from 0°C to 70°C.

SN5473, SN54LS73A . . . J OR W PACKAGE
SN7473 . . . N PACKAGE
SN74LS73A . . . D OR N PACKAGE
(TOP VIEW)



'73
FUNCTION TABLE

INPUTS				OUTPUTS	
$\overline{CLR}$	CLK	J	K	Q	$\overline{Q}$
L	X	X	X	L	H
H	⊓	L	L	Q_0	$\overline{Q}_0$
H	⊓	H	L	H	L
H	⊓	L	H	L	H
H	⊓	H	H	TOGGLE	

'LS73A
FUNCTION TABLE

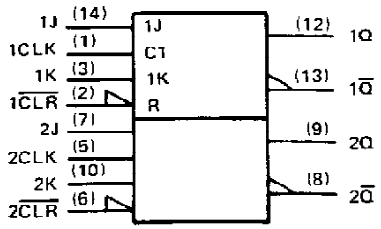
INPUTS				OUTPUTS	
$\overline{CLR}$	CLK	J	K	Q	$\overline{Q}$
L	X	X	X	L	H
H	↓	L	L	Q_0	$\overline{Q}_0$
H	↓	H	L	H	L
H	↓	L	H	L	H
H	↓	H	H	TOGGLE	
H	H	X	X	Q_0	$\overline{Q}_0$

FOR CHIP CARRIER INFORMATION, CONTACT THE FACTORY

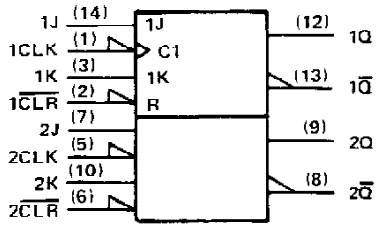
PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

logic symbols†

'73



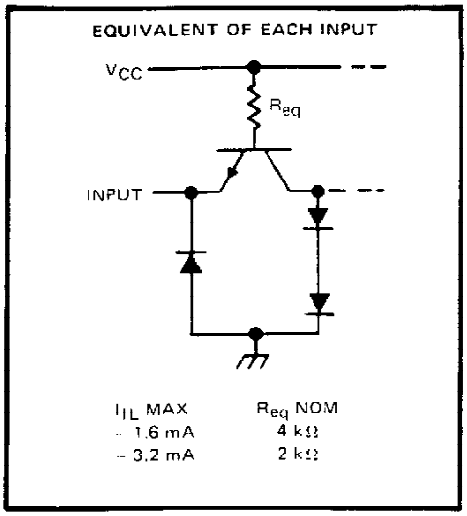
'LS73A

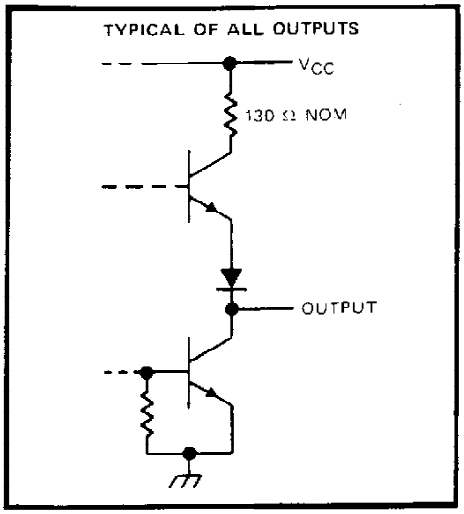


†These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

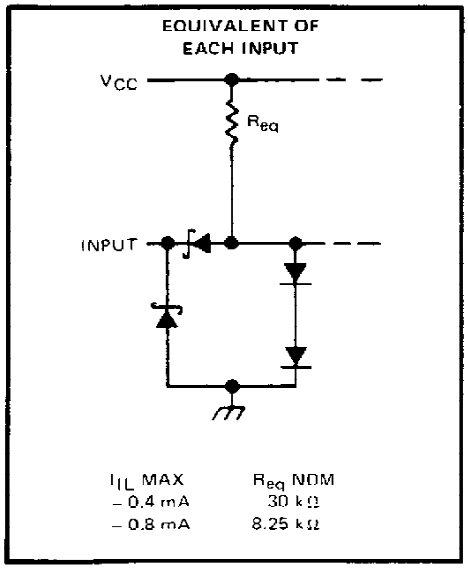
schematics of inputs and outputs

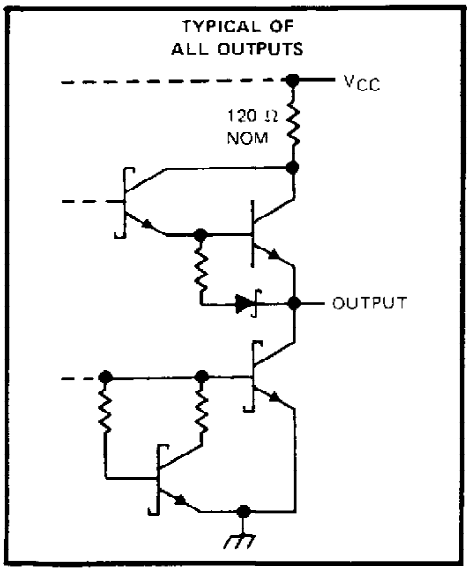
'73





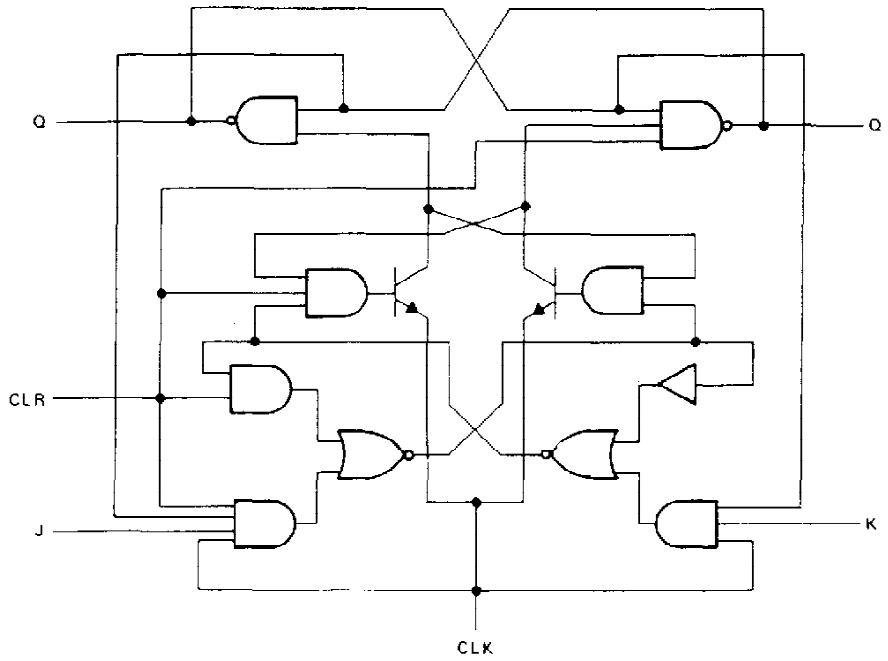
'LS73



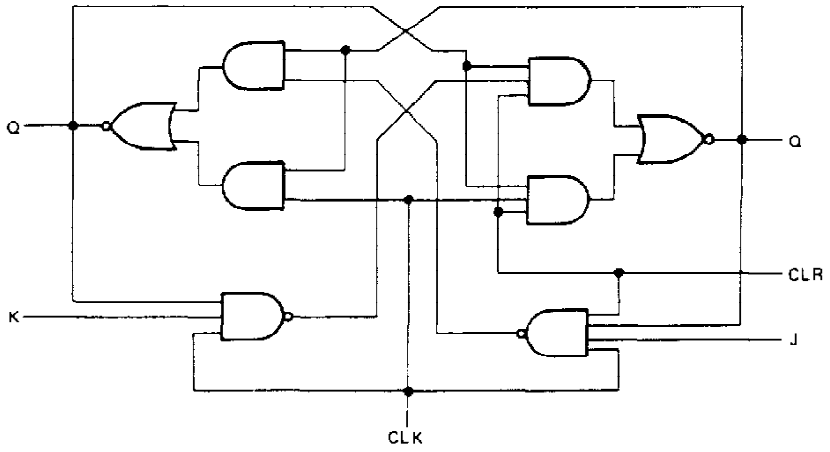


logic diagrams (positive logic)

'73



'LS73A



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (See Note 1) . . . . . 7 V
Input voltage: '73 . . . . . 5.5 V
'LS73A . . . . . 7 V
Operating free-air temperature range: SN54' . . . . . −55°C to 125°C
SN74' . . . . . 0° C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

			SN5473			SN7473			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
I_{OH}	High-level output current				−0.4			−0.4	mA
I_{OL}	Low-level output current				16			16	mA
t_w	Pulse duration	CLK high	20			20			ns
		CLK low	47			47			
		$\overline{CLR}$ low	25			25			
t_{su}	Input setup time before CLK↑		0			0			ns
t_h	Input hold time data after CLK↓		0			0			ns
T_A	Operating free-air temperature		−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	SN5473			SN7473			UNIT
			MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}		V_{CC} = MIN, I_I = −12 mA			−1.5			−1.5	V
V_{OH}		V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OH} = −0.4 mA	2.4	3.4		2.4	3.4		V
V_{OL}		V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OL} = 16 mA		0.2	0.4		0.2	0.4	V
I_I		V_{CC} = MAX, V_I = 5.5 V			1			1	mA
I_{IH}	J or K	V_{CC} = MAX, V_I = 2.4 V			40			40	μA
	$\overline{CLR}$ or CLK				80			80	
I_{IL}	J or K	V_{CC} = MAX, V_I = 0.4 V			−1.6			−1.6	mA
	$\overline{CLR}$				−3.2			−3.2	
	CLK				−3.2			−3.2	
I_{OS}§		V_{CC} = MAX	−20		−57	−18		−57	mA
I_{CC}¶		V_{CC} = MAX, See Note 2		10	20		10	20	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time.
¶ Average per flip-flop.
NOTE 2: With all outputs open, I_{CC} is measured with the Q and $\overline{Q}$ outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER#	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{max}			R_L = 400 Ω, C_L = 15 pF	15	20		MHz
t_{PLH}	$\overline{CLR}$	$\overline{Q}$			16	25	ns
t_{PHL}		Q			25	40	ns
t_{PLH}	CLK	Q or $\overline{Q}$			16	25	ns
t_{PHL}					25	40	ns

#f_{max} = maximum clock frequency; t_{PLH} = propagation delay time, low-to-high-level output; t_{PHL} = propagation delay time, high-to-low-level output.
NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

recommended operating conditions

			SN54LS73A			SN74LS73A			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.7			0.8	V
I_{OH}	High-level output current				−0.4			−0.4	mA
I_{OL}	Low-level output current				4			8	mA
f_{clock}	Clock frequency		0		30	0		30	MHz
t_w	Pulse duration	CLK high	20			20			ns
		$\overline{CLR}$ low	25			20			
t_{su}	Set up time-before CLK↓	data high or low	20			20			ns
		$\overline{CLR}$ inactive	20			20			
t_h	Hold time-data after CLK↓		0			0			ns
T_A	Operating free-air temperature		−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†			SN54LS73A			SN74LS73A			UNIT
					MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}		V_{CC} = MIN,	I_I = −18 mA				−1.5			−1.5	V
V_{OH}		V_{CC} = MIN, I_{OH} = −0.4 mA	V_{IH} = 2 V,	V_{IL} = MAX,	2.5	3.4		2.7	3.4		V
V_{OL}		V_{CC} = MIN, I_{OL} = 4 mA	V_{IL} = MAX,	V_{IH} = 2 V,		0.25	0.4		0.25	0.4	V
		V_{CC} = MIN, I_{OL} = 8 mA	V_{IL} = MAX,	V_{IH} = 2 V,					0.35	0.5	
I_I	J or K	V_{CC} = MAX,	V_I = 7 V				0.1			0.1	mA
	$\overline{CLR}$						0.3			0.3	
	CLK						0.4			0.4	
I_{IH}	J or K	V_{CC} = MAX,	V_I = 2.7 V				20			20	μA
	$\overline{CLR}$						60			60	
	CLK						80			80	
I_{IL}	J or K	V_{CC} = MAX,	V_I = 0.4 V				−0.4			−0.4	mA
	$\overline{CLR}$ or CLK						−0.8			−0.8	
I_{OS}§		V_{CC} = MAX,	See Note 4		−20		−100	−20		−100	mA
I_{CC} (Total)		V_{CC} = MAX,	See Note 2			4	6		4	6	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.
NOTE 2: With all outputs open, I_{CC} is measured with the Q and $\overline{Q}$ outputs high in turn. At the time of measurement, the clock input is grounded.
NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the 54 family and the 74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
f_{max}			R_L = 2 kΩ,	C_L = 15 pF	30	45		MHz
t_{PLH}	$\overline{CLR}$ or CLK	Q or $\overline{Q}$				15	20	ns
t_{PHL}						15	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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